L Number	Hits	Search Text	DB	Time stamp
25	2	("1930905" "2137852").PN.	USPAT	2004/11/03 08:27
26	14	4546658.URPN.	USPAT	2004/11/03 08:27
89	2	("5578766").PN.	USPAT;	2004/11/03 08:52
			US-PGPUB;	,
			EPO; JPO;	
		,	DERWENT	
90	2	("6450040").PN.	USPAT;	2004/11/03 09:11
			US-PGPUB;	
	i		EPO; JPO;	
			DERWENT	
91	9	(USPAT	2004/11/03 08:52
-		"3761784" "4480488" "5770803" "5886543").PN.		
92	4		USPAT	2004/11/03 09:07
93	8		USPAT	2004/11/03 09:20
i		("4701660") or ("3088323") or ("4556814") or ("4419598")).PN.		
94	7	4419598.URPN.	USPAT	2004/11/03 09:15
95	6	("2311617" "3283590" "3417322" "3492513" "3739201"	USPAT	2004/11/03 09:17
-		"3805601").PN.		
96	89951	310/\$7.ccls.	USPAT;	2004/11/03 09:20
			US-PGPUB;	
•			EPO; JPO;	
			DERWENT	
97	431	310/\$7.ccls. and (force near3 (sens\$4 evaluat\$5 estimat\$5 cell rate	USPAT;	2004/11/03 09:21
		comput\$5 detect\$4 test\$4 meter gauge transducer measur\$4 indicat\$4	US-PGPUB;	
		identif\$4 monitor\$4 determina\$4)).clm.	EPO; JPO;	
			DERWENT	
98	51	(310/\$7.ccls. and (force near3 (sens\$4 evaluat\$5 estimat\$5 cell rate	USPAT;	2004/11/03 09:25
		comput\$5 detect\$4 test\$4 meter gauge transducer measur\$4 indicat\$4	US-PGPUB;	
		identif\$4 monitor\$4 determina\$4)).clm.	EPO; JPO;	
			DERWENT	
) and (semiconductor substrate).clm.		
99	19		USPAT;	2004/11/03 09:26
		comput\$5 detect\$4 test\$4 meter gauge transducer measur\$4 indicat\$4	US-PGPUB;	
		identif\$4 monitor\$4 determina\$4)).clm.	EPO; JPO;	
			DERWENT	
į) and (semiconductor substrate).clm.) and electrode.clm.		
100	19	1 (USPAT	2004/11/03 09:35
-		"4512431" "4604544" "4816713" "5371472" "5537883" "5682000"		
.		"5739626" "5747671" "5777231" "5777239" "5852245"		
.		"5886456" "6271621" "6396200").PN.		
101	0	6617764.URPN.	USPAT	2004/11/03 09:39
142	2	("4546658").PN.	USPAT;	2004/11/03 11:18
			US-PGPUB;	
1			EPO; JPO;	
		,	DERWENT	
143	1	(("4546658").PN.) and (substrate semiconductor silicon)	USPAT;	2004/11/03 11:19
			US-PGPUB;	
			EPO; JPO;	
			DERWENT	
	2518	(73/760,763,774,781,777,862.381,862.474,862.68,862.621).CCLS.	USPAT;	2004/11/02 09:40
			US-PGPUB;	
			EPO; JPO;	
			DERWENT	
-	311	((73/760,763,774,781,777,862.381,862.474,862.68,862.621).CCLS.) and	USPAT;	2004/11/03 09:20
		(force near3 (sens\$4 evaluat\$5 estimat\$5 cell rate comput\$5 detect\$4	US-PGPUB;	
}		test\$4 meter gauge transducer measur\$4 indicat\$4 identif\$4 monitor\$4	EPO; JPO;	
		determina\$4)).clm.	DERWENT	
İ				

-	56	(((73/760,763,774,781,777,862.381,862.474,862.68,862.621).CCLS.) and (force near3 (sens\$4 evaluat\$5 estimat\$5 cell rate comput\$5 detect\$4 test\$4 meter gauge transducer measur\$4 indicat\$4 identif\$4 monitor\$4 determina\$4)).clm.	USPAT; US-PGPUB; EPO; JPO; DERWENT	2004/11/03 09:25
-	16) and (semiconductor substrate).clm. ((((73/760,763,774,781,777,862.381,862.474,862.68,862.621).CCLS.) and (force near3 (sens\$4 evaluat\$5 estimat\$5 cell rate comput\$5 detect\$4 test\$4 meter gauge transducer measur\$4 indicat\$4 identif\$4 monitor\$4 determina\$4)).clm.	USPAT; US-PGPUB; EPO; JPO; DERWENT	2004/11/03 09:26
	13) and (semiconductor substrate).clm.) and electrode.clm. (((((73/760,763,774,781,777,862.381,862.474,862.68,862.621).CCLS.) and (force near3 (sens\$4 evaluat\$5 estimat\$5 cell rate comput\$5 detect\$4 test\$4 meter gauge transducer measur\$4 indicat\$4 identif\$4 monitor\$4 determina\$4)).clm.	USPAT; US-PGPUB; EPO; JPO; DERWENT	2004/11/02 09:41
-	6) and (semiconductor substrate).clm.) and electrode.clm.) and current ((((((73/760,763,774,781,777,862.381,862.474,862.68,862.621).CCLS.) and (force near3 (sens\$4 evaluat\$5 estimat\$5 cell rate comput\$5 detect\$4 test\$4 meter gauge transducer measur\$4 indicat\$4 identif\$4 monitor\$4 determina\$4)).clm.	USPAT; US-PGPUB; EPO; JPO; DERWENT	2004/11/02 09:49
,) and (semiconductor substrate).clm.) and electrode.clm.) and current.clm.		
-	7	("3351786" "4320664" "4703658" "4771639" "4833929" "4993266" "5142914").PN.	USPAT	2004/11/02 09:45
-	3 7	5349873.URPN. (((((((73/760,763,774,781,777,862.381,862.474,862.68,862.621).CCLS.) and (force near3 (sens\$4 evaluat\$5 estimat\$5 cell rate comput\$5 detect\$4 test\$4 meter gauge transducer measur\$4 indicat\$4 identif\$4 monitor\$4 determina\$4)).clm.	USPAT USPAT; US-PGPUB; EPO; JPO; DERWENT	2004/11/02 09:48 2004/11/02 10:03
) and (semiconductor substrate).clm.) and electrode.clm.) and current) not ((((((73/760,763,774,781,777,862.381,862.474,862.68,862.621).CCLS.) and (force near3 (sens\$4 evaluat\$5 estimat\$5 cell rate comput\$5 detect\$4 test\$4 meter gauge transducer measur\$4 indicat\$4 identif\$4 monitor\$4 determina\$4)).clm.		
) and (semiconductor substrate).clm.) and electrode.clm.) and current.clm.)		
-	10	(("5341688") or ("4833929") or ("4680606") or ("4419598")).PN.	USPAT; US-PGPUB; EPO; JPO; DERWENT	2004/11/02 10:04
-	4	((("5341688") or ("4833929") or ("4680606") or ("4419598")).PN.) and current	USPAT; US-PGPUB; EPO; JPO; DERWENT	2004/11/02 11:18
-	175813	kabushiki.as.	USPAT; US-PGPUB; EPO; JPO; DERWENT	2004/11/02 11:19
-	2438	kabushiki.as. and (force pressure transducer).ti.	USPAT; US-PGPUB; EPO; JPO;	2004/11/02 11:20
-	124	(kabushiki.as. and (force pressure transducer).ti.) and semiconductor.ab.	DERWENT USPAT; US-PGPUB; EPO; JPO;	2004/11/02 11:20
-	150	(kabushiki.as. and (force pressure transducer).ti.) and electrode.ab.	DERWENT USPAT; US-PGPUB; EPO; JPO; DERWENT	2004/11/02 11:20
L	<u> </u>	I	DEKARIAI	<u> </u>

-	28	((kabushiki.as. and (force pressure transducer).ti.) and semiconductor.ab.)	USPAT;	2004/11/02 11:42
		and electrode.ab.	US-PGPUB; EPO; JPO;	
•			DERWENT	
	7	("3351786" "4320664" "4703658" "4771639" "4833929"	USPAT	2004/11/02 11:27
-	' .	"4993266" "5142914").PN.	OSIAI	2004/11/02 11.2/
ļ _	2	("3149488" "4833929").PN.	USPAT	2004/11/02 11:28
_	19	4993266.URPN.	USPAT	2004/11/03 11:18
_	2	("4993266").PN.	USPAT;	2004/11/02 12:05
	_	(1330200)11.11	US-PGPUB;	20002 .2.00
			EPO; JPO;	
			DERWENT	
_	105	((73/760,763,774,781,777,862.381,862.474,862.68,862.621).CCLS.) and	USPAT;	2004/11/02 12:06
•		electrode near5 ((top face end oppos\$5) and (bottom face other end	US-PGPUB;	
1		oppos\$5))	EPO; JPO;	
			DERWENT	
-	40	((((73/760,763,774,781,777,862.381,862.474,862.68,862.621).CCLS.)	USPAT;	2004/11/02 12:59
		and (force near3 (sens\$4 evaluat\$5 estimat\$5 cell rate comput\$5 detect\$4	US-PGPUB;	
		test\$4 meter gauge transducer measur\$4 indicat\$4 identif\$4 monitor\$4	EPO; JPO;	
		determina\$4)).clm.	DERWENT	
				-
) and electrode near5 ((top face end oppos\$5) and (bottom face other end		
		oppos\$5))		
- *	16		USPAT;	2004/11/02 12:07
		and (force near3 (sens\$4 evaluat\$5 estimat\$5 cell rate comput\$5 detect\$4	US-PGPUB;	
		test\$4 meter gauge transducer measur\$4 indicat\$4 identif\$4 monitor\$4	EPO; JPO;	
		determina\$4)).clm.	DERWENT	
) and (semiconductor substrate).clm.) and electrode near5 ((top face end		
		oppos\$5) and (bottom face other end oppos\$5))		
	24	((((73/760,763,774,781,777,862.381,862.474,862.68,862.621).CCLS.)	USPAT;	2004/11/02 13:01
-	24	and (force near3 (sens\$4 evaluat\$5 estimat\$5 cell rate comput\$5 detect\$4	US-PGPUB;	2004/11/02 13:01
		test\$4 meter gauge transducer measur\$4 indicat\$4 identif\$4 monitor\$4	EPO; JPO;	
		determina\$4)).clm.	DERWENT	;
		4000		
) and electrode near5 ((top face end oppos\$5) and (bottom face other end		
		oppos\$5))) NOT		
		(((((73/760,763,774,781,777,862.381,862.474,862.68,862.621).CCLS.)		
		and (force near3 (sens\$4 evaluat\$5 estimat\$5 cell rate comput\$5 detect\$4		
		test\$4 meter gauge transducer measur\$4 indicat\$4 identif\$4 monitor\$4		
		determina\$4)).clm.		
) and (semiconductor substrate).clm.) and electrode near5 ((top face end		,
•		oppos\$5) and (bottom face other end oppos\$5)))	LICDATE	2004/11/02 00.50
-	6	1 (((((USPAT;	2004/11/03 08:50
		and (force near3 (sens\$4 evaluat\$5 estimat\$5 cell rate comput\$5 detect\$4	US-PGPUB;	
		test\$4 meter gauge transducer measur\$4 indicat\$4 identif\$4 monitor\$4	EPO; JPO; DERWENT	
		determina\$4)).clm.	DERWENT	
) and electrode near5 ((top face end oppos\$5) and (bottom face other end		
		oppos\$5))) NOT		
		(((((73/760,763,774,781,777,862.381,862.474,862.68,862.621).CCLS.)		
		and (force near3 (sens\$4 evaluat\$5 estimat\$5 cell rate comput\$5 detect\$4		
1.		test\$4 meter gauge transducer measur\$4 indicat\$4 identif\$4 monitor\$4		
		determina\$4)).clm.		
) and (semiconductor substrate).clm.) and electrode near5 ((top face end		
		oppos\$5) and (bottom face other end oppos\$5)))) and (semiconductor)		
- '	14		USPAT	2004/11/02 13:06
-	19	1 (USPAT	2004/11/02 13:09
		"4294105" "4372173" "4546658" "4642508" "4789804" "5023503" "4789804" "5023503"		
		"5232063" "5362929" "5684276" "5852229" "5869763"		
L	L	"5946795" "5962786" "6080939").PN.	L	<u> </u>